

September 2015

# FDS89141

# Dual N-Channel Shielded Gate PowerTrench® MOSFET 100 V, 3.5 A, 62 m $\Omega$

#### **Features**

- Shielded Gate MOSFET Technology
- Max  $r_{DS(on)} = 62 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 3.5 \text{ A}$
- Max  $r_{DS(on)} = 100 \text{ m}\Omega$  at  $V_{GS} = 6 \text{ V}$ ,  $I_D = 2.8 \text{ A}$
- High performance trench technology for extremely low r<sub>DS(on)</sub>
- High power and current handling capability in a widely used surface mount package
- 100% UIL Tested
- RoHS Compliant

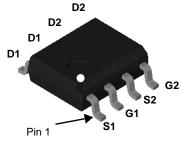


#### **General Description**

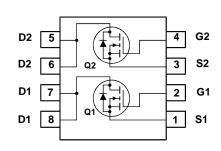
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized for  $r_{DS(on)}$ , switching performance and ruggedness.

#### **Applications**

- Synchronous Rectifier
- Primary Switch For Bridge Topology







# MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
$V_{DS}$	Drain to Source Voltage			100	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous			3.5	۸
ID	-Pulsed			18	_ A
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	37	mJ
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	31	W
	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1b)	1.6	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temp	erature Range		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	(Note 1)	40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	78	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS89141	FDS89141	SO-8	13 "	12 mm	2500 units

# Electrical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

Symbol	Parameter	Parameter Test Conditions		Тур	Max	Units
Off Chara	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		69		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA

#### On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2	3.1	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$ , referenced to 25 °C		-9		mV/°C
		$V_{GS} = 10 \text{ V}, I_D = 3.5 \text{ A}$		47	62	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 2.8 \text{ A}$		63	100	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 3.5 \text{ A}, T_J = 125 \text{ °C}$		81	107	1
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_D = 3.5 \text{ A}$		14.7		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, f = 1MHz	299	398	pF
C <sub>oss</sub>	Output Capacitance		70	93	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		4.7	7	pF
$R_g$	Gate Resistance		1.0		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		V <sub>DD</sub> = 50 V, I <sub>D</sub> = 3.5 A,		5	10	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 3.			1.4	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = 10 V, R <sub>GEN</sub>	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		9.8	20	ns
t <sub>f</sub>	Fall Time				2.2	10	ns
$Q_{g(TOT)}$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V			5.1	7.1	nC
$Q_{g(TOT)}$	Total Gate Charge	V <sub>GS</sub> = 0 V to 5 V	$V_{DD} = 50 \text{ V},$		2.9	4.1	nC
Q <sub>gs</sub>	Gate to Source Charge		$I_D = 3.5 \text{ A}$		1.4		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge				1.3		nC

### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 3.5 \text{ A}$	(Note 2)	0.8	1.3	V
	Source to Drain Diode Polward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2 \text{ A}$	(Note 2)	8.0	1.2	
t <sub>rr</sub>	Reverse Recovery Time	-I <sub>F</sub> = 3.5 A, di/dt = 100 A/μs		33	53	ns
Q <sub>rr</sub>	Reverse Recovery Charge			23	37	nC

<sup>1.</sup> R<sub>0JA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a) 78°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b) 135°C/W when mounted on a minimun pad

<sup>2.</sup> Pulse Test: Pulse Width < 300 $\mu$ s, Duty cycle < 2.0%. 3. Starting T  $_J$  = 25°C, L = 3.0 mH, I  $_{AS}$  = 5.0 A, V  $_{DD}$  = 100 V, V  $_{GS}$  = 10V.

# Typical Characteristics ( N-Channel) T<sub>J</sub> = 25°C unless otherwise noted

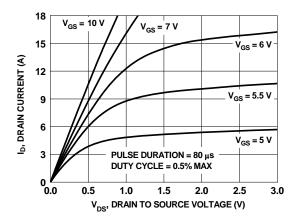


Figure 1. On-Region Characteristics

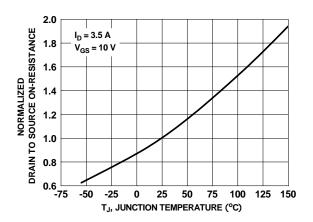


Figure 3. Normalized On-Resistance vs Junction Temperature

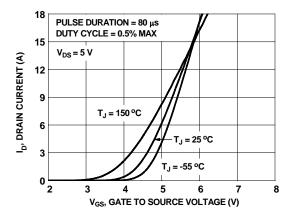


Figure 5. Transfer Characteristics

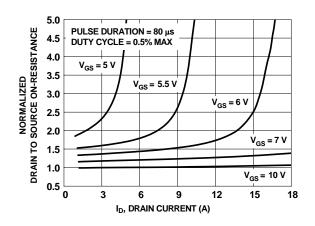


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

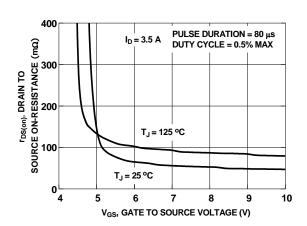


Figure 4. On-Resistance vs Gate to Source Voltage

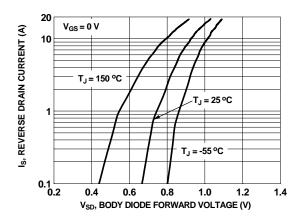


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics ( N-Channel) T<sub>J</sub> = 25°C unless otherwise noted

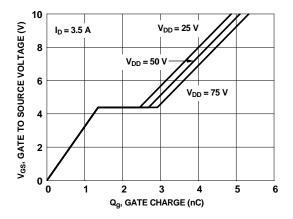


Figure 7. Gate Charge Characteristics

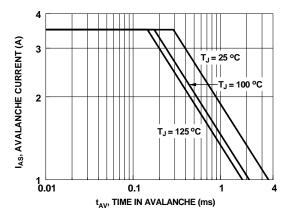


Figure 9. Unclamped Inductive Switching Capability

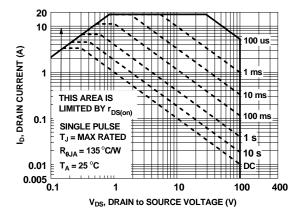


Figure 11. Forward Bias Safe Operating Area

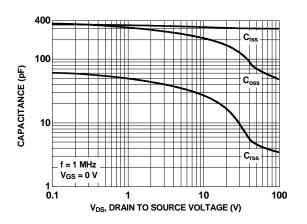


Figure 8. Capacitance vs Drain to Source Voltage

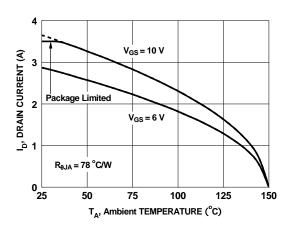


Figure 10. Maximum Continuous Drain Current vs Ambient Temperature

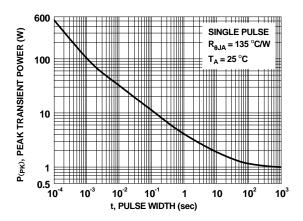


Figure 12. Single Pulse Maximum Power Dissipation

# Typical Characteristics ( N-Channel) T<sub>J</sub> = 25°C unless otherwise noted

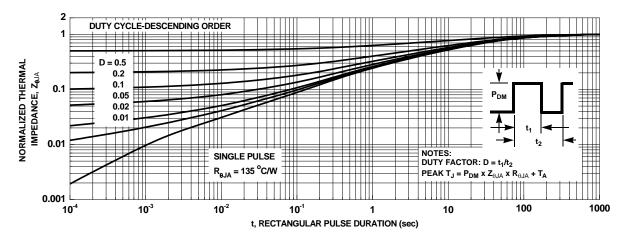


Figure 13. Junction-to-Ambient Transient Thermal Response Curve



ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdt/Patent-Marking.pdf">www.onsemi.com/site/pdt/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and exp

#### **PUBLICATION ORDERING INFORMATION**

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative